

SLOVENSKI STANDARD SIST EN 60115-2:2015

01-september-2015

Nadomešča:

SIST EN 140100:2008

Fiksni upori za elektronsko opremo - 2. del: Področna specifikacija: nežični upori z majhno močjo

Fixed resistors for use in electronic equipment - Part 2: Sectional specification : Fixed low-power non-wirewound resistors

Festwiderstände zur Verwendung in Geräten der Elektronik / Teil 2 / Rahmenspezifikation - Verbleite niedrig belastbare Schichtwiderstände (Standards. Iteh.ai)

Résistances fixes utilisées dans les <u>équipements élec</u>troniques - Partie 2: Spécification intermédiaire: Résistances fixes à broche à couches, à faible dissipation

Ta slovenski standard je istoveten z: EN 60115-2:2015

ICS:

31.040.10 Fiksni upor Fixed resistors

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SIST EN 60115-2:2015

iTeh STANDARD PREVIEW (standards.iteh.ai)

<u>SIST EN 60115-2:2015</u> https://standards.iteh.ai/catalog/standards/sist/7e338596-b303-449d-a8e9e8430b13cf4c/sist-en-60115-2-2015

EUROPEAN STANDARD

EN 60115-2

NORME EUROPÉENNE

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English Version

Fixed resistors for use in electronic equipment - Part 2: Sectional specification: Leaded fixed low power film resistors (IEC 60115-2:2014, modified)

Résistances fixes utilisées dans les équipements électroniques - Partie 2: Spécification intermédiaire: Résistances fixes à broches à couches, à faible dissipation (IEC 60115-2:2014, modifiée) Festwiderstände zur Verwendung in Geräten der Elektronik
- Teil 2: Rahmenspezifikation - Verbleite niedrig belastbare
Schichtwiderstände
(IEC 60115-2:2014, modifiziert)

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European Committee for Electrotechnical Standardization Comité Européen de Normalisation Electrotechnique Europäisches Komitee für Elektrotechnische Normung

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Foreword

This document (EN 60115-2:2015) has been prepared by CLC/TC 40XB "Resistors".

The following dates are fixed:

•	latest date by which this document has to be implemented at	(dop)	2015-12-15
	national level by publication of an identical national standard or		
	by endorsement		

• latest date by which the national standards conflicting with this (dow) 2017-12-15 document have to be withdrawn

This document supersedes EN 140100:2008.

Clauses, subclauses, notes, tables, figures and annexes which are additional to those in IEC 60115-2:2014 are prefixed "Z".

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1 Modification to Clause 2

After the 1st paragraph, add the following note:

NOTE The readers of this European Standard are advised of the corresponding European documents listed in the normative Annex ZA, which take precedence over the International Standards listed in this clause. The precedence also applies to all normative references made within this document.

2 Modification to 3.1

At the end, add the following:

3.1.Z1

nominal resistance

R.

resistance value for which the resistor has been designed, and which is generally used for denomination of the resistor

Note 1 to entry: The definition of nominal resistance, $R_{\rm n}$, is identical to the definition of rated resistance, $R_{\rm r}$, in EN 60115-1:2011. Therefore nominal resistance, $R_{\rm n}$, may be applied wherever rated resistance, $R_{\rm r}$, is required, e.g. in a quality assessment scheme.

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3 Modifications to 3.3 (standards.iteh.ai)

At the beginning of the 2nd paragraph, *replace* "Two general end product levels" by "Three general end product levels".

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After the 5th paragraph (Examples for Level R4c/); add the following:

NOTE Z1 Product classification level P adopts and succeeds the former Version A.

Replace the 6th paragraph (Level P is the suitable basis ...) by

Level R – High-performance and high-reliability electronic equipment, where the requirement for established reliability and for an approved failure rate level applies in addition to the criteria of Level P.

Examples for Level R include military & defence equipment, avionics and aerospace applications.

NOTE Z2 Product classification level R adopts and succeeds the former Version E.

Replace the 7th paragraph (Each level shall be used ...) by

Each level shall be used in individual detail specifications, except for Level P and Level R, which may be used in combined detail specifications.

4 Modification to 4.6

Replace the 4th paragraph by

The upper category temperature (UCT), which is used for test procedures, shall be the same as the maximum element temperature (MET).

Modification to 5.2.10

Replace the last paragraph by

This test is mandatory only for resistors categorized as Level P or as Level R.

Modification to 5.2.12.5

Replace the 2nd entry for air pressure (1 kPa ...) by

 $p_{\rm amb}$ = 1 kPa, for resistors categorized as Level P or as Level R.

Modification to 5.2.14

Replace the last paragraph by

The extended endurance of this test is mandatory only for resistors categorized as Level P or as Level R.

Modification to 5.2.17

Replace the last paragraph by STANDARD PREVIEW

This test is mandatory only for resistors categorized as Level P or as Level R.

SIST EN 60115-2:2015 Modification to 5.2.18 https://standards.iteh.ai/catalog/standards/sist/7e338596-b303-449d-a8e9-

e8430b13cf4c/sist-en-60115-2-2015

Replace the entry for the solvent temperature by

$$\mathcal{G}_{\text{bath}} = (50^0_{-5}) \,^{\circ}\text{C}$$

10 Modification to 5.2.19

Replace the entry for solvent temperature by

$$g_{\text{bath}} = (50^0_{-5}) \,^{\circ}\text{C}$$

11 Modifications to 5.2.21

Replace the 2^{nd} list entry for positive discharges ($n_{pos} = 3 \dots$) by

 $n_{\rm pos}$ = 3 for resistors categorized as Level P or as Level R

Replace the 2^{nd} list entry for negative discharges ($n_{neq} = 3 \dots$) by

 n_{neg} = 3 for resistors categorized as Level P or as Level R

-6-

12 Modification to 5.2.22

Replace the last paragraph by

This test is mandatory only for resistors categorized as Level P or as Level R.

13 Modification to 6.2

Replace Footnote a in Table 3 by

^a Test is mandatory only for resistors categorized as Level P or as Level R.

14 Modification to 6.5

Replace the explanation for MET by

MET is the maximum element temperature, MET = UCT.

15 Modifications to 9.4

Replace the 1st paragraph by STANDARD PREVIEW

9.4.Z1 General

(standards.iteh.ai)

The procedures for Qualification Approval testing are given in EN 60115-1:2011, Clause Q.2, with the test procedures described in EN 60115-1:2013[\$\tilde{Q}.2\frac{14}{60115-2:2015}\$

https://standards.iteh.ai/catalog/standards/sist/7e338596-b303-449d-a8e9-

Replace the last paragraph by e8430b13cf4c/sist-en-60115-2-2015

9.4.Z2 Granting the approval for products classified to Level G or to Level P

The qualification approval for classification level G or P shall be granted after successful completion of 1 000 h of the test endurance at 70 °C and all other tests of Table 5.

9.4.Z3 Granting the approval for products classified to Level R

The qualification approval for classification level R, failure rate level E5 shall be granted after successful completion of 1 000 h of the test Endurance at 70 °C and all other tests of Table 5.

Thereafter, the qualification approval for classification level R, failure rate level E6 shall be granted after successful completion of 8 000 h of the test Endurance at 70 °C.

The qualification approval for classification level R shall be withdrawn if the 8 000 h test is not completed successfully.

16 Modification to 9.5

Replace the 1st sentence of the 1st paragraph by

The schedule for the lot-by-lot and periodic tests for Quality Conformance Inspection of resistors categorized as level G, P or R are given in Table 6.

17 Modification to 9.6

Replace the 1st paragraph by

This sectional specification does not support the capability approval as described in EN 60115-1:2011, Q.3.

18 Modification to 9.7

Replace the 1st paragraph by

The provisions of EN 60115-1:2011, Q.4 shall apply, and the test schedules of Table 5 and Table 6 shall be used.

19 Modification to 9.8

Replace the 1st paragraph by

The provisions of EN 60115-1:2011, Q.1.7 shall apply, except that the inspection level shall be reduced to S-2.

20 Modification to 19.19 STANDARD PREVIEW

Replace the 1st paragraph by

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Certified test records according to EN 60115-1:2011, Q.1.5 can be supplied, if agreed upon between the manufacturer and the customer.

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https://standards.iteh.ai/catalog/standards/sist/7e338596-b303-449d-a8e9-e8430b13cf4c/sist-en-60115-2-2015

21 Modifications to Table 5

In Group 7, Test 4.25.1.8, *replace* the bracketed term of the entry in the 1st column by

(applicable only to resistors categorized as Level P or as Level R)

In Group 12, Test 4.39, *replace* the bracketed term of the entry in the 1st column by

(applicable only to resistors categorized as Level P or as Level R)

In Group 13, Test 4.19, *replace* the bracketed term of the entry in the 1st column by

(applicable only to resistors categorized as Level P or as Level R)

In Group 14, Test 4.27, *replace* the bracketed term of the entry in the 1st column by

(applicable only to resistors categorized as Level P or as Level R)

22 Modifications to Table 6

In Group C2, Test 4.25.1.8, *replace* the bracketed term of the entry in the 1st column by (applicable only to resistors categorized as Level P or as Level R)

In Group F, Test 4.19, *replace* the bracketed term of the entry in the 1st column by (applicable only to resistors categorized as Level P or as Level R)

In Group G, Test 4.27, *replace* the bracketed term of the entry in the 1st column by (applicable only to resistors categorized as Level P or as Level R)

23 Modifications to Clause D.1

In the list of letter symbol explanations, **add** the new entry after the entry for R_n :

 R_r Rated resistance, $R_r = R_n$ Ω

In the list of letter symbol explanations, $\it{replace}$ the respective entries for temperature \it{T} to $\Delta \it{T}_{max}$ by

	iTeh STANDARD PREVIEW	
E	Temperature, e.g. as an atmospheric condition for testing (also written as T)	°C
Ç	Low temperature of a change of temperature test (also written as T_{A})	°C
ç	High temperature of a change of temperature test (also written as $T_{\rm B}$)	°C
S	https://standards.iteh.ai/catalog/standards/sist/7e338596-b303-449d-a8e9- Ambient temperature (also written as Famb) 0115-2-2015	°C
ç	Bath temperature, e.g. in solvent resistance or solder bath tests (also written as $T_{\rm bath}$)	°C
ç	Maximum temperature, maximum element temperature (also written as $T_{\sf max}$)	°C
ç	Rated temperature (also written as $T_{\rm r}$)	°C
S	Upper temperature, e.g. in a respective temperature sequence (also written as T_{sup})	°C
Δ	Temperature rise (also written as ΔT)	K
Δ	$ ho_{ m max}$ Maximum permissible temperature rise (also written as $\Delta T_{ m max}$)	K

24 Modifications to Annex X

Delete Annex X (Cross reference for references to the prior revision of this standard).

25 New Annex ZA

Add the new normative Annex ZA (see attached Annex ZA) on correspondences for normative references.

26 New Annex ZX

Add the new informative Annex ZX (see attached Annex ZX) providing cross references for references to the predecessor of this specification.

27 Modifications to the Bibliography

Replace the Bibliography by the Bibliography providing references to European Standards (see attached Bibliography).

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<u>SIST EN 60115-2:2015</u> https://standards.iteh.ai/catalog/standards/sist/7e338596-b303-449d-a8e9-e8430b13cf4c/sist-en-60115-2-2015

Annex ZA

(normative)

Normative references to international publications with their corresponding European publications

The following documents, in whole or in part, are normatively referenced in this document and are indispensable for its application. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

NOTE 1 When an International Publication has been modified by common modifications, indicated by (mod), the relevant EN/HD applies.

NOTE 2 Up-to-date information on the latest versions of the European Standards listed in this annex is available here: www.cenelec.eu.

<u>Publication</u>	<u>Year</u>	<u>Title</u>	EN/HD	<u>Year</u>
IEC 60062	2004	Marking codes for resistors and capacitors	EN 60062 + corrigendum Jan.	2005 2007
IEC 60068-1	2013	Environmental testing - Part 1: General and guidance	EN 60068-1	2014
IEC 60068-2-1	-iTe	Part 2-1: Tests - Test A: Cold	EN 60068-2-1	-
IEC 60068-2-2	-	Environmental testing - Part 2-2: Tests - Tests B: Dry heat	EN 60068-2-2	-
IEC 60068-2-6	2007 https://stand	SIST EN 60115-2:2015 Environmental testing: /sist/7e338596-b303-449d- Part 2-6: Jests - Test Fc; Vibration (sinusoidal)	EN 60068-2-6	2008
IEC 60068-2-20	2008	Environmental testing - Part 2-20: Tests – Test T – Test methods for solderability and resistance to soldering heat of leaded devices	EN 60068-2-20	2008
IEC 60115-1 (mod.)	2008	Fixed resistors for use in electronic equipment - Part 1: Generic specification	EN 60115-1	2011
IEC 60286-1	-	Packaging of components for automatic handling - Part 1: Tape packaging of components with axial leads on continuous tapes	EN 60286-1	-
IEC 60294	2012	Measurement of the dimensions of a cylindrical component having two axial terminations	EN 60294	2012
IEC 60301	-	Preferred diameters of wire terminations of capacitors and resistors	EN 60301	-
IEC 61193-2	2007	Quality assessment systems – Part 2: Selection and use of sampling plans for inspection of electronic components and packages	EN 61193-2	2007
IEC 61760-1	2006	Surface mounting technology – Part 1: Standard method for the specification or surface mounting components (SMDs)	EN 61760-1 f	2006

Annex ZX (informative)

Cross reference for references to the predecessor of this specification

This sectional specification is presented in a new structure compared to the preceding document. The following table provides a cross reference for all references to specific elements of the predecessor of this Sectional Specification.

EN 140100:2008	EN 60115-2:2015	Notes
Clause/Subclause	Clause/Subclause	Notes
1	_	The subject is covered by Clauses 1 and 8.
1.1	1	_
1.2	8	_
2	_	The subject is covered by Clauses 4, 5 and 6.
2.1	_	The subject is covered by Clauses 4 and 6.
2.1.1	4.1	The prior Table 1 is succeeded by Table 1.
2.1.2	Coh ST 4.2ND A D	The prior Table 2 is succeeded by Table 4.
2.1.3	6.4 DAI	
2.1.4	(standards	The prior Tables 3a and 3b are succeeded by Tables 3a and 3b, respectively.
2.2 https://s	4 <mark>SIST EN 60115</mark>	-2:2015 xist/7e338596_b303_449d_a8e9_
2.2.1	e84 3 0 8 13cf4c/sist-en-	5B4 7 6 55 65 7 6 65 65 11 7 4 46 6 7
2.2.2	4.5	_
2.2.3	4.6	_
2.2.4	4.7	_
2.2.5	4.9	_
2.2.6	4.8	_
2.2.7	_	The subject is left to the ruling of the detail specification.
2.3	5.2	_
2.3.1	5.2.13	_
2.3.2	5.2.11	
2.3.3	5.2.12.5	_
2.3.4	5.2.9 5.2.10	_
2.3.5	5.2.7	_
2.3.6	5.2.8	_
2.3.7	5.2.4	_
2.3.8	5.2.17	_

2.3.9	5.2.22	-
2.3.10	5.2.21	
2.3.11	5.2.20	_
2.4	5.1	_
2.4.1	5.1.1	_
2.4.2	5.1.2	_
2.4.3	5.1.3	_
3	9	_
3.1	9.1	_
3.1.1	9.2.2	_
3.1.2	9.3	_
3.2	9.4	The information of the prior Table A.1 concerning Qualification Approval is implemented in Table 5.
3.3	9.5	The information of the prior Table A.1 concerning Quality Conformance Inspection is implemented in Table 6a, for lot-by-lot tests, and in Table 6b, for periodic tests.
3.4	9.7	
3.5	eli STANDAK	D FREVIEW
3.6	(standards	iteh.ai)
А		The subject is covered by 9.4 and 9.5.
B https://s	standards.iteh.ai/ Catalog/standards/	s st/ 7e338596-b303-449d-a8e9-
B.1	e8430b13cf4c/sist-en-	<u>601</u> 15-2-2015
B.2	D.2	_
Bibliography	Bibliography	_

Bibliography

EN 60027-1, Letter symbols to be used in electrical technology – Part 1: General (IEC 60027-1)

EN 60060-1, High-voltage test techniques – Part 1: General definitions and test requirements (IEC 60060-1)

EN 60068-2-1:1993 1), Environmental testing – Part 2-1: Tests – Test A: Cold (IEC 60068-2-1:1990)

EN 60068-2-2:1993 ²⁾, Basic environmental testing procedures – Part 2-2: Tests – Tests B: Dry heat (IEC 60068-2-2:1974)

EN 60068-2-13, Environmental testing – Part 2-13: Tests – Test M: Low air pressure (IEC 60068-2-13)

EN 60068-2-14, Environmental testing – Part 2-14: Tests – Test N: Change of temperature (IEC 60068-2-14)

EN 60068-2-21, Environmental testing – Part 2-21: Tests – Test U: Robustness of terminations and integral mounting devices (IEC 60068-2-21)

EN 60068-2-30, Environmental testing – Part 2-30: Tests – Test Db: Damp heat, cyclic (12 h + 12 h cycle) (IEC 60068-2-30)

EN 60068-2-45, Environmental testing – Part 2-45: Tests – Test Xa and guidance: Immersion in cleaning solvents (IEC 60068-2-45)

EN 60068-2-78, Environmental testing – Part 2-78: Tests – Test Cab: Damp heat, steady state (IEC 60068-2-78)

EN 60286-2, Packaging of components for automatic handling – Part 2. Packing of components with unidirectional leads on continuous tapes (IEC 60286-2)

EN 60440, Method of measurement of non-linearity in resistors (IEC 60440)

EN 60695-11-5, Fire hazard testing – Part 11-5; Test flames – Needle-flame test method – Apparatus, confirmatory test arrangement and guidance (IEC 60695-11-5)

EN 60717, Method for the determination of the space required by capacitors and resistors with unidirectional terminations (IEC 60717)

EN 61192-3, Workmanship requirements for soldered electronic assemblies – Part 3: Through-hole mount assemblies (IEC 61192-3)

EN 61340-3-1, *Electrostatics – Part 3-1: Methods for simulation of electrostatic effects – Human body model (HBM) electrostatic discharge test waveforms* (IEC 61340-3-1)

EN 80000 (all parts), Quantities and units (IEC 80000 (all parts))

EN ISO 80000 (all parts), Quantities and units (ISO 80000 (all parts))

IEC 60063, Preferred number series for resistors and capacitors

IEC 60195, Method of measurement of current noise generated in fixed resistors

IECQ 03-3, IEC Quality Assessment System for Electronic Components (IECQ) – Rules of Procedure – Part 3: IECQ Approved Component Products, Related Materials & Assemblies Scheme

IECQ 03-3-1, IEC Quality Assessment System for Electronic Components (IECQ) – Rules of Procedure – Part 3-1: IECQ Approved Component Products, Related Materials & Assemblies Scheme, IECQ Approved Component – Technology Certification (IECQ AC-TC)

¹⁾ EN 60068-2-1:1993 is replaced by EN 60068-2-1:2007, *Environmental testing – Part 2-1: Tests – Test A: Cold* (IEC 60068-2-1:2007).

²⁾ EN 60068-2-2:1993 is replaced by EN 60068-2-2:2007, *Environmental testing – Part 2-1: Tests – Test B: Dry heat* (IEC 60068-2-2:2007).